UNIKC Semiconductor

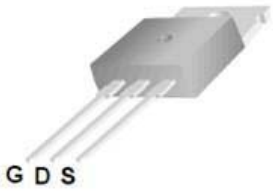
RoHS Compliant

P2610ATG

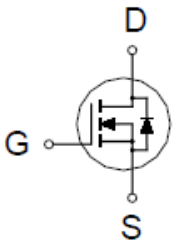
N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	26mΩ @V_{GS} = 10V	50A



TO-220



100% UIS tested

ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current	T_C = 25 °C	I_D	50	A
	T_C = 100 °C		31	
Pulsed Drain Current[1]		I_{DM}	200	
Avalanche Current		I_{AS}	77	
Avalanche Energy	L = 0.3mH	E_{AS}	900	mJ
Power Dissipation	T_C = 25 °C	P_D	128	W
	T_C = 100 °C		51	
Operating Junction & Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C
Lead Temperature ($^1/_{16}$" from case for 10 sec.)		T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		0.97	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	
Case-to-Heatsink	$R_{\theta CS}$	0.5		

[1]Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0V, I_D = 250μA	100			V
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250μA	1.5	2.3	4.0	
Gate-Body Leakage	I_{GSS}	V_{DS} = 0V, V_{GS} = ±20V			±250	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 80V, V_{GS} = 0V			1	μA
		V_{DS} = 80V, V_{GS} = 0V , T_J = 125 °C			10	
On-State Drain Current[1]	$I_{D(ON)}$	V_{DS} = 10V, V_{GS} = 10V	50			A
Drain-Source On-State	$R_{DS(ON)}$	V_{GS} = 10V, I_D = 25A		21	26	mΩ
Forward Transconductance[1]	g_{fs}	V_{DS} = 40V, I_D = 25A		38		S
DYNAMIC						
Input Capacitance	C_{iss}	V_{GS} = 0V, V_{DS} = 25V, f = 1MHz		4900		pF
Output Capacitance	C_{oss}			887		
Reverse Transfer Capacitance	C_{rss}			186		
Total Gate Charge[2]	Q_g	V_{DS} = 80V, V_{GS} = 10V, ID = 50A		79		nC
Gate-Source Charge[2]	Q_{gs}			31		
Gate-Drain Charge[2]	Q_{gd}			30		
Turn-On Delay Time[2]	$t_{d(on)}$	V_{DD} = 50V, $I_D \cong$ 50A, V_{GS} = 10V, R_{GEN} = 25Ω		25		nS
Rise Time[2]	t_r			250		
Turn-Off Delay Time[2]	$t_{d(off)}$			110		
Fall Time[2]	t_f			140		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current	I_S				50	A
Forward Voltage[1]	V_{SD}	I_F = I_S, V_{GS} = 0V			1.5	V
Reverse Recovery Time	t_{rr}			100		nS
Reverse Recovery Charge	Q_{rr}			380		nC

[1]Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

[2]Independent of operating temperature.

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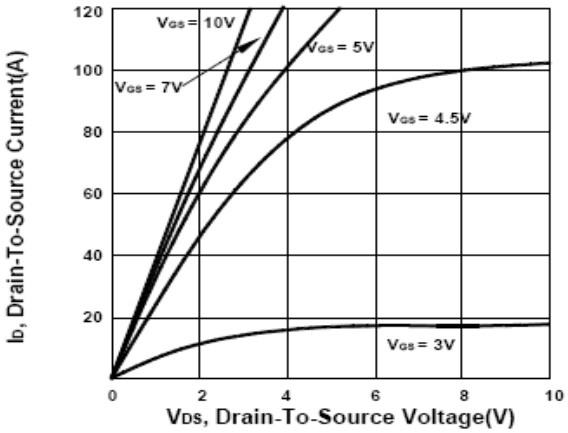
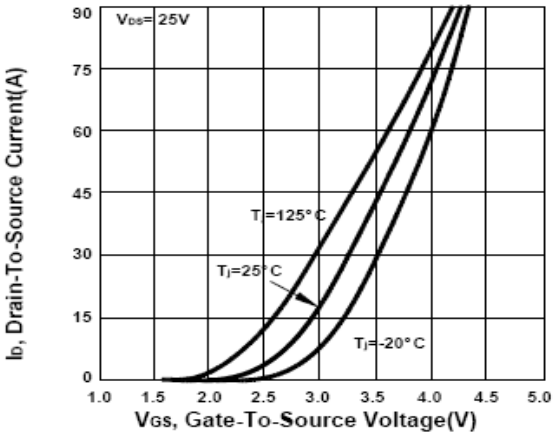
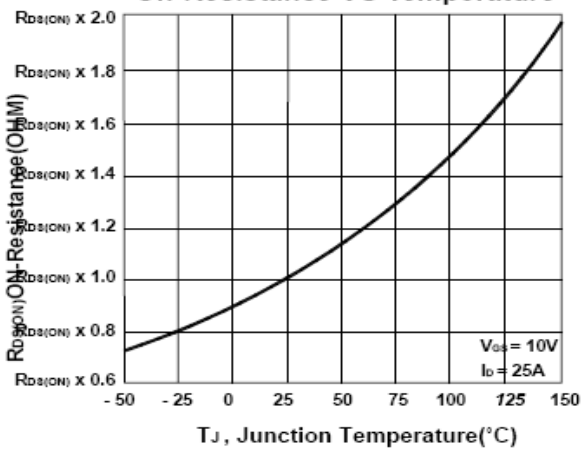
Output Characteristics



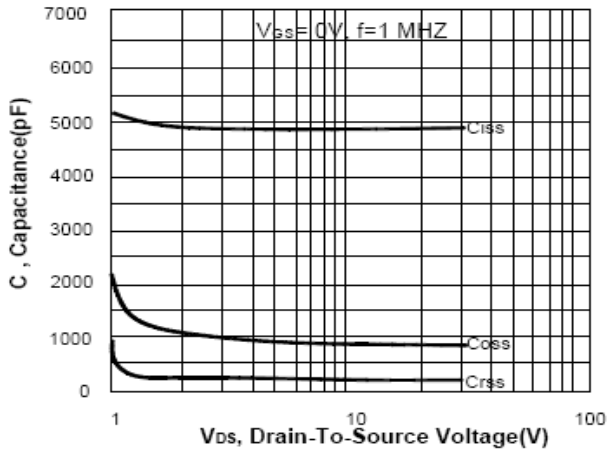
Transfer Characteristics



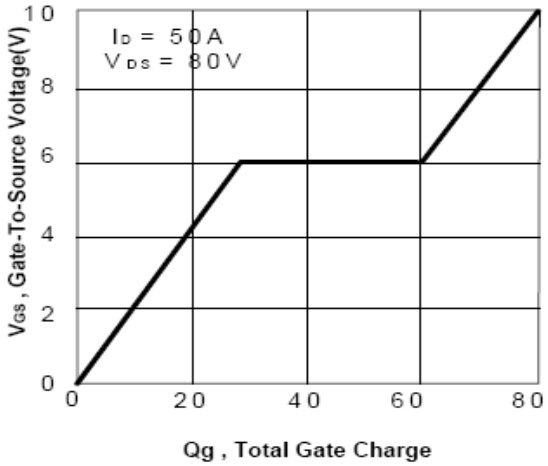
On-Resistance VS Temperature



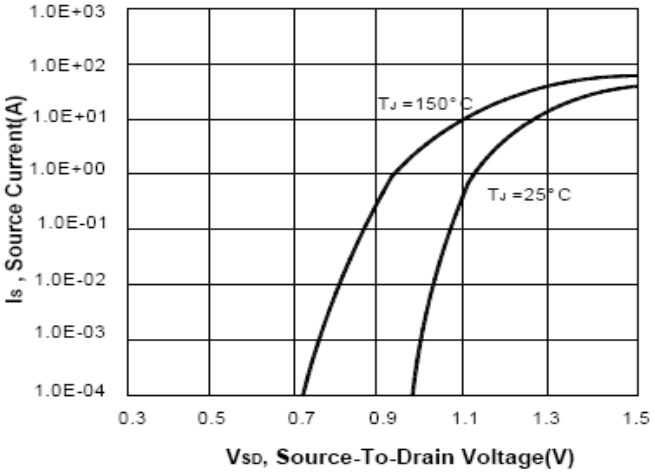
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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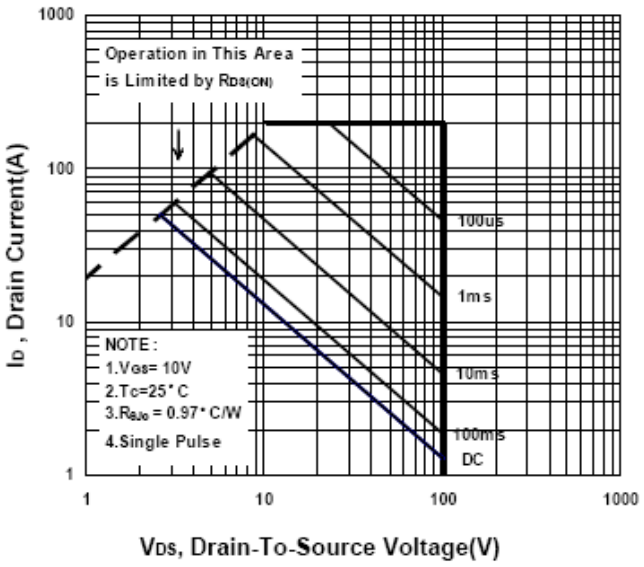
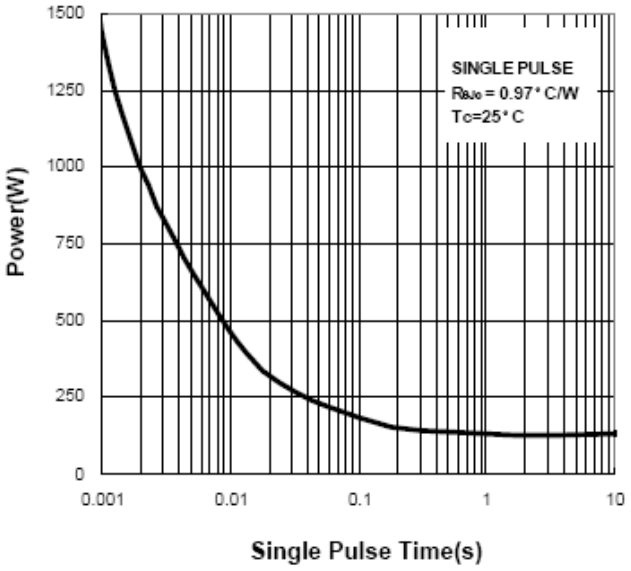
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve